

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A testing apparatus which comprises a plurality of testing module slots to which different types of testing modules for testing a device under test are optionally mounted, comprising:

a first testing module;

a second testing module; and

a synchronization controlling unit provided separately from said first testing module and said second testing module, said synchronization controlling unit comprising:

operation order holding means for holding information indicating that a test operation by [[a]]_said first testing module among said plurality of testing modules should be performed before a test operation by [[a]]_said second testing module among said plurality of testing modules;

trigger return signal receiving means for receiving a trigger return signal from said first testing module, ~~said trigger return signal indicating that said first testing module has completed said test operation thereof, when said test operation of said first testing module has been completed;~~ and

trigger signal supplying means for supplying a trigger signal to said second testing module, said trigger signal indicating that said second testing module should start said test operation thereof, when said trigger return signal receiving means receives said trigger return signal.

2. (Original) A testing apparatus as claimed in claim 1, wherein said first testing module is an arbitrary waveform adjustor for generating and supplying an arbitrary analog waveform to said device under test,

said second testing module is a phase characteristics tester for receiving an analog waveform outputted by said device under test in response to said analog waveform supplied from said arbitrary waveform adjustor, and testing phase characteristics of said analog waveform,

said operation order holding means holds information indicating that said phase characteristics tester should perform a receiving operation of said analog waveform from said device under test, after said arbitrary waveform adjustor performs a supply operation of said analog waveform to said device under test,

said trigger return signal receiving means receives said trigger return signal from said arbitrary waveform adjustor, said trigger return signal indicating that said arbitrary waveform adjustor has completed said supply operation, when said supply operation at a predetermined time of said analog waveform has completed by said arbitrary waveform adjustor, and

said trigger signal supplying means supplies said trigger signal to said phase characteristics tester, said trigger signal indicating that said phase characteristics tester should start said receiving operation of said analog waveform from said device under test, when said trigger return signal receiving means receives said trigger return signal.

3. (Original) A testing apparatus as claimed in claim 1, wherein said trigger return signal receiving means and said trigger signal supplying means are a multiplexer circuit for obtaining each of a plurality of said trigger return signals from each of said plurality of testing modules, selecting one of said trigger return signals obtained from said first testing module, and supplying said selected trigger return signal to said second testing module as said trigger signal, and

said operation order holding means is a flip-flop circuit for holding a select signal for controlling said multiplexer circuit to select said trigger return signal.

4. (Original) A testing apparatus as claimed in claim 1, wherein said first testing module performs first and second test operations in parallel,

said operation order holding means holds information indicating that said test operation by said second testing module should be performed after said first test operation by said first testing module, and information indicating that a test operation by a third testing module among said plurality of testing modules should be performed after said second test operation by said first testing module,

said trigger return signal means receives a first trigger return signal from said first testing module, said first trigger return signal indicating that said first testing module has completed said first test operation, when said first test operation of said first testing module has been completed, and a second trigger return signal from said first testing module, said second trigger return signal indicating that said first testing module has completed said second test operation, when said second test operation of said first testing module has been completed, and

said trigger signal supplying means supplies a first trigger signal to said second testing module, said first trigger signal indicating that said second testing module should start said test operation thereof, when said trigger return signal receiving means receives said first trigger return signal, and a second trigger signal to said third testing module, said second trigger signal indicating that said third testing module should start said test operation thereof, when said trigger return signal receiving means receives said second trigger return signal.

5. (New) A testing apparatus as claimed in claim 1, wherein said trigger return signal receiving means receives a trigger return signal from said first testing module, when said test operation of said first testing module has been completed, said trigger return signal indicating that said first testing module has completed said test operation thereof.